



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of

SWAINE et al

Atty. Ref.: 550-205

Serial No. 09/773,387

Group: 2121

Filed: February 1, 2001

Examiner: James Rutten

For: TRACING OUT-OF-ORDER DATA

\* \* \* \* \*

Assistant Commissioner for Patents  
Washington, DC 20231

April 27, 2004

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Sir:

**INFORMATION DISCLOSURE STATEMENT**

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the attached form PTO-1449, a copy of each of which is enclosed.

The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Respectfully submitted,

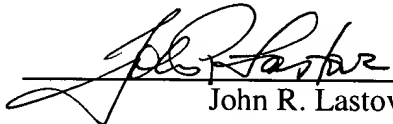
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## INFORMATION DISCLOSURE CITATION

ATTY. DOCKET NO.

550-205

**APPLICANT**

SWAINE et al

FILING DATE

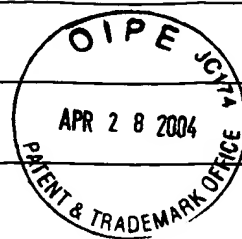
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**GROUP**

2121



(Use several sheets if necessary)

## U.S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

[illegible]

**OTHER DOCUMENTS** (including Author, Title, Date, Pertinent pages, etc.)

		U.S. Application Serial No. 09/792,643 filed February 26, 2001	
		U.S. Application Serial No. 09/876,220 filed June 8, 2001.	
		ARM IHI 0014 Revision C - Embedded Trace Macrocell Specification .	
		ARM DDI 0157F – ETM9 (Rev. 1) Technical Reference Manual	
		ARM DDI 0158D-ETM7 (Rev. 1) Technical Reference Manual	
		ARM IHI 0014 Revision I-Embedded Trace Macrocell Spec	
		John Hennessy et al., Computer Organization and Design, The Hardware/Software Interface, Morgan Kaufman Publishers, Inc. Second Edition, 1998, page 351.	
*Examiner			Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.